

Defect-oriented test generation and fault simulation in the environment of MOSCITO

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Digital design flow with test activities

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FPGA design flow with automated test generation

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High-level synthesis and test in the MOSCITO-based virtual laboratory

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Integration of digital test tools to the internet-based environment MOSCITO

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Internet-based collaborative test generation with MOSCITO [Electronic resource]

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Virtual laboratory for research in dependable microelectronics

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